

ABSTRACT**Method of analyzing an integrated circuit, method of observation and their associated installations**

The invention relates to a method for analyzing an integrated circuit including:

- a step (102) for applying laser radiation at a point on the surface of the circuit;
- a step (106) for exciting the circuit thus subjected to laser radiation by applying an electrical excitation signal;
- a step (106) for collecting the response of the circuit to the excitation, the circuit being subjected to laser radiation;
- a step (106) for measuring the phase difference between the response to the excitation of the circuit subjected to laser radiation and a reference response of the circuit in the absence of laser radiation applied to the circuit.

The invention also relates to an associated observation method and installation.

Fig. 2